

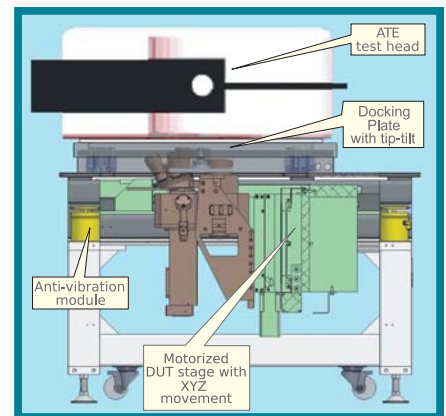
SEMICAPS 3000 CONFIGURATION

INVERTED TESTER-DOCKED SYSTEM



Features

- Adaptable to various ATE
- Easily moved from Tester to Tester
- Custom docking for all ATE platforms
- High resolution stage with 20nm resolution and 0.5 μ m repeatability
- Centric and Aplanatic Refractive Solid Immersion Lens (RSIL) option
- CAD interface option
- Compatible with thermal management solutions
- Techniques include:
 - Laser Timing Probe (LTP) with frequency mapping for locating signals
 - Scanning Optical Microscopy (SOM) with best-in-class sensitivity for static and dynamic laser induced techniques
 - Photon Emission Microscopy (PEM) with LN2-free, low noise InGaAs or Si-CCD camera
 - Thermal Microscopy (THM) with InSb camera



ATE-Docked